

SOC Encounter Homework

助教聯絡方式：

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Description

In this homework, you are going to implement your Verilog **HW3** designs into GDSII layout. Please add to your synthesized design **with scan chains**, and include *pad cells* for SOC Encounter. Finally, you need to submit an electronic *report* (upload to FTP) describing what you have done. (There is no particular report style. However, please include the specified items.)

Design Libraries & Data Preparation

You can choose to add pad cells after synthesis, or before synthesis (use a wrapper-like gate-level top module with pad cells to include your RTL, more preferable). However, notice that the input/output delay's definitions will be different. The SDC file is not part of the library, so you should create it by yourself, or you can use *write_sdc* in DV to generate it automatically. If the memory compiler is needed, related information can be found in Verilog Lab2. Be sure to generate all the memory data/libraries for SOC Encounter. Finally, you can check the Lab for more hints.

Submission Deadline:

Online Submission (FTP):

Deadline	2018/06/12 12:00
IP	140.112.18.84
Port	1232
Account	CVSD_STUDENT
Password	cvsd2018

Please submit a zipped PDF report named *StudentID_HW6.zip*, including:

Basic (75%)

1. Topic & timing/delay information.
 - A. 15% (只要有看到 timing report or sdc content，基本上都會滿分)
 - B. 有一些不合常理的情況（例如 number of path = 0），會拿不到滿分

2. Synthesis reports & DFT-related reports (summarized).
 - A. 20% (只要有 Synthesis reports 和 DFT-related reports (必須顯示有 scan chain 發生作用, 譬如 port、area 增加之類))
 - B. 有人重複貼了相同內容上去或是只貼了 Synthesis reports 上去。這就
只有拿到 Synthesis reports 分數 (12%)
 - C. 只貼 DFT-related reports or scan chain 相關訊息上去, 分數會高於只
貼 Synthesis reports, 理由是這一步驟應該是為了確認有無操作 DFT。
3. Final chip layout figure (big & clear enough to see) & chip size (um x um).
 - A. 20%(只要有圖、有 size 出現就會滿分)
 - B. 只有圖 (12%)
 - C. 只有 size (12%)
 - D. 另外有其他因素, 會被減少一點分數 (例如: 不是” Final” chip layout
figure)
4. Pre-layout & post-layout simulation results (summarized).
 - A. 20% (只要有測 Pre-layout & post-layout, 就會滿分)
 - B. 只測 Pre-layout (12%)
 - C. 有一個 testbench 沒有過, 會少一分。

Advanced (25%)

5. Complete power planning (VDD/VSS/IOVDD/IOVSS number, power
ring/strips width, voltage drop & electron migration figures...).
 - A. 10% (有說明、要求的圖都有就會滿分)
 - B. 只有說明及 power ring/strips (4~7%)
 - C. 提供更少資訊, 會再更少分數
6. Better I/O & modules' placement (explanations, amoeba view...).
 - A. 10% (有說明、有圖就會滿分)
 - B. 只有說明 (5%~8%)
 - C. 提供更少資訊, 會再更少分數
7. Other related discussions.
 - A. 5% (除非特別好、特別針對其他因素討論, 才會滿分)
 - B. 有基本的說明 (3~4%)

C. 只貼圖（2%）